


<b>Search Notes</b> 	<b>Application/Control No.</b> 10589915	<b>Applicant(s)/Patent Under Reexamination</b> CHONG ET AL.
	<b>Examiner</b> ROBERT HUBER	<b>Art Unit</b> 2892

### SEARCHED

Class	Subclass	Date	Examiner
257	314, 613	5/14/08	RH
711	104	5/14/08	RH
257	2 - 5	12/8/08	RH

### SEARCH NOTES

Search Notes	Date	Examiner
Inventor Search - EAST (USPAT, USGPUB, USOCR) - see printout	5/13/08	RH
PLUS search - keywords: chalcogenide, phase, change, pcrum, multiple, plurality, many, layer, film, memory, temperature, electrode, contact	5/14/08	RH
EAST search (USPAT, USGPUB, USOCR, FPRS, EPO, JPO, DERWENT, IBM) - see printout	5/13/08 - 5/15/08, 5/21/08	RH
Suggested EAST Search from Thao Le: @ad<= 20040219 and GeTe same Sb.sub.2Te.sub.3	5/21/08	RH
Updated EAST search (USPAT, USGPUB, USOCR, FPRS, EPO, JPO, DERWENT, IBM) - see printout	12/8/08	RH

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

--	--